Search Notes

Application/Control No.	Applicant(s)/Pate Reexamination	ent under	
10/632,196	PATFIELD, KE\	′IN M.	
Examiner	Art Unit		
SYED ZAIDI	2616		

SEARCHED					
Class	Subclass	Date	Examiner		
370	352	5/29/2008	SZ		
370	351	5/29/2008	SZ		
370	359	5/29/2008	SZ		
370	379	5/29/2008	SZ		
370	353	5/29/2008	SZ		
370	355	5/29/2008	SZ		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	L				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	5/29/2008	SZ		
Inventors : PATFIELD, KEVIN M.	5/29/2008	SZ		
(IEEE Xplore Database(http://ieeexplore.ieee.org/Xp lore/DynWel.jsp)	5/29/2008	SZ		
(370/352 370/351 370/359 370/379 370/353 370/355 370/357).CCLS.	5/29/2008	SZ		
Consulted with SPE Nick Corsaro	5/29/2008	SZ		